

Integrating the Right Decoupling Capacitor: Busting the 9 Greatest Capacitor Myths

James P. Muccioli & Dale L. Sanders

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1. Understanding the Role of Decoupling

- 2. Testing Decoupling Capacitors
 - Myth #1
- 3. Evaluating Decoupling (Capacitors-Only)
 - Myth #2
 - ✓ Myth #3
 - Myth #4
- 4. PDS Placement & Mounting Parasitics
 - Myth #5
 - Myth #6
- 5. PDS with Low-Inductance Capacitors
- 6. Cost/Build-of-Materials (BOM)
 - Myth #7
 - Myth #8
- 7. Conclusion/Questions
 - Myth #9



Power Distribution System (PDS)

- Is not a perfect DC supply due to parasitics.
- PDS needs defined voltage levels that include max & min values to ensure IC functionality.
- Solution State State
- Output: Set of the set of the
 - Current Ripples supply instantaneous current (energy).
 - Bypass transients filter high frequency switching noise.



- Decoupling capacitors consist of:
 - Large value caps bulk caps (mid-freq).
 - Small value caps bypass/H.F. caps (highfreq).



Milliorn, Gary, "Power Supply Design for PowerPCTM Processors," Freescale Semiconductor Application Note AN2447, Rev. 1.1, Sept 2004.



What are the PDS design issues?

- Inductance
 - Caps
 - Vias
 - Component mounting
 - PCB plane
 - Package
- PCB real-estate
 - Number of caps & vias
 - Location/effectiveness
 - Placement cost
 - Multiple power planes

Signal Integrity (SI)

- Number of vias (routing)
- Manufacturing cost (multiple plane PCBs)
- Functionality



Understanding the Role of Decoupling



Steve Weir, Scott McMorrow, Teraspeed® Consulting Group LLC, "High Performance FPGA Bypass Filter Networks," DesignCon 2005, Santa Clara, CA, February 2005.

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<u>Myth #1</u> – Industry has uniform standards to test & evaluate the performance of decoupling capacitors.



There are 3 main tests to evaluate decoupling capacitors:

Network Analyzer

Insertion Loss

Time-Domain Analysis

Ripple

Transients

Impedance Analyzer

Impedance



Test Fixtures – What is the test set-up to evaluate a capacitor?

- Without an industry standard, there are 2 main schools of thought:
 - Capacitor-in-system
 - Capacitor-only



Capacitor-in-system

Advantages

- More "real world" measurements
- Allows vias to be included; current path in vias can be difficult to model at H.F. (specifically for multi-terminal capacitors).

Disadvantages

- Application specific measurement
 - Limited to specific parameters PCB (material & thickness), via size, plane stack-up, etc.



Testing Decoupling Capacitors

Capacitor-in-system

- Passive PCB
 - Insertion Loss
 - Time-Domain
 - Impedance
- Sample PCB
 - Insertion Loss
 - Time-Domain
 - Impedance
- Active PCB
 - Time-Domain







Testing Decoupling Capacitors

Capacitor-in-system – type of measurement

Across cap

- Measure cap-only.
 - Not a true system measurement.
- PCB Edge
 - Not a true system measurement for IC
- IC package dimension
 - Measure PDS network.
 - Allows mounting, via, and plane impedance to be included.



Top Right Picture - Milliorn, Gary, "Power Supply Design for PowerPCTM Processors," Freescale Semiconductor Application Note AN2447, Rev. 1.1, Sept 2004. Novak, Istvan, "Power Distribution Measurements," DesignCon 2003 East, High-Performance System Design Conference, Boston, MA, June 23-25, 2003. <u>TecForum HP-TF1 presentation</u>



Capacitor-only

Advantages

- Accurately measures capacitor
- Allows for accurate models of capacitor

Disadvantages

- PCB structure parameters can be difficult to model.
 - Component mounting, current loops, via influence, plane stack-up, etc.



Capacitor-only Fixture Microwave solderless fixture 50 ohm coplanar/microstrip PCBs





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Summary <u>Myth #1</u> – Industry has uniform standards to test & evaluate the performance of decoupling capacitors.

- There are no uniform industry standards to test and evaluate decoupling capital
- Types of testing
 - Time-Domain Analysis
 - Network Apalyz r
 - Impedance Ar alyzer
- Types of fixtures
 - Capacitor-in-system
 - Capacitor-only



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<u>Myth #2</u> – Adding more capacitance will fix the problem.

<u>Myth #3</u> – For bulk caps, ESR is main concern; and only electrolytic & tantalum can be used.



Time-Domain Input signal = 10 MHz, 1 nsec rise/fall time, 5V applitude, 80/20 duty cycle.

- Ripple Tantalum and Electrolytic both need 47uF {Add more capacitance} vs. 1.0uF for the MLCC.
- Transients 1.0uF MLCC substantially improved switching transients.

Sanders, Muccioli, North, and Slattery, "<u>The Quantitative Measurement of the Effectiveness of Decoupling Capacitors in Controlling Switching Transients from Microprocessors</u>," CARTS 2005 USA, Palm Springs, CA, March 2005.

Technology In Balance



Insertion Loss – ENA 100 kHz to 8.5GHz.

- I.OuF MLCC shows comparable or better attenuation than both the electrolytic or tantalum capacitors with 2% the capacitance value.
- Inductance inhibits the transfer of energy (current) out of the cap.

Sanders, Muccioli, North, and Slattery, "<u>The Quantitative Measurement of the Effectiveness of Decoupling Capacitors in Controlling Switching Transients from Microprocessors</u>," CARTS 2005 USA, Palm Springs, CA, March 2005.

Technology in Balance



Summary <u>Myth #2</u> – Adding more capacitance will fix the problem.

- Adding more capacitance will in prove the ripple thus lowering the insertion loss/impedance at lower frequencies.
- However, capacitor parasitic inductance affects:
 - The efficiency of energy transfer out of the capacitor.
 - Reduces high frequency transient response.



Summary <u>Myth #3</u> – For bulk caps, ESR is main concern; and only electrolytic & tantalum can be used.

- SR is a concern, however, inductance should also be considered.
- MLCC Technoleg
 - Can significantly reduce the amount of capacital cerequired in a circuit.
 - Can be manufactured with comparable capacitance values as electrolytic and tantalum for decoupling applications.

Technology In Balance

<u>Myth #4</u> – Smaller package size is always better for reducing inductance, the capacitance value has no affect on inductive behavior.



MLCC – Smaller is better – 0603 has less inductance than 0805, 1206, & 1812.

- To meet total capacitance requirements typically small caps increase the number of caps needed. (Package size limits number of layers.)
- Larger number of caps require more vias & greater distance from IC. (More PCB space)

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Technology in Balance

D.L. Sanders, J.P. Muccioli, A.A. Anthony, and D.J. Anthony, "X2Y® Technology Used for Decoupling," Published by the IEE, New EMC issues in Design: Techniques, Tools and Components Event Symposium, April 28, 2004.



X2Y[®] Technology – package size comparison.

The X2Y[®] Technology maintains or improves low-inductive performance as package size increases.

Technology In Balance

D.L. Sanders, J.P. Muccioli, A.A. Anthony, and D.J. Anthony, "X2Y® Technology Used for Decoupling," Published by the IEE, New EMC issues in Design: Techniques, Tools and Components Event Symposium, April 28, 2004.



The capacitance value has no affect on the inductive behavior of a cap.

Physical geometry of the current loop through the capacitor affects the parasitic inductance.

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Balance

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X2Y[®] Technology – capacitive value comparison.

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Summary <u>Myth #4</u> – Smaller package size is always better for reducing inductance, the capacitance value has no affect on inductive behavior.

- Std MLCC Technology smaller is better.
- - Structure promotes mutual inductance cancellation that lowers over-all net inductance.
 - Inductance improves with:
 - Larger capacitance value (more layers).
 - Larger package (more layers).



What is the performance benefit of low-inductive caps?

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- Each MLCC measured individually
- Total (5) MLCC = 0.398uF

Technology In Balance

- X2Y[®] total capacitance value = 0.44uF
- Note: package size differences



Measurements made on 50ohm Coplanar PCB with Ground Plane.

0.44uF

MLCC cumulative measured

X2Y[®] total capacitance value =

Note: package size differences

Total (5) MLCC = 0.5μ F

D.L. Sanders, J.P. Muccioli, A.A. Anthony, and D.J. Anthony, "X2Y® Technology Used for Decoupling," Published by the IEE, New EMC issues in Design: Techniques, Tools and Components Event Symposium, April 28, 2004.

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Steve Weir, Scott McMorrow, Teraspeed® Consulting Group LLC, "High Performance FPGA Bypass Filter Networks," DesignCon 2005, Santa Clara, CA, February 2005.

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<u>Myth #5</u> – Bypass capacitor placement with respect to ICs or other caps is not very critical.



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Distance between IC and Cap:

- Larger current loop
- More inductance Cap L Less effective Via l Via L R2 R1 Plane Spreading L Vcc_plane_FPGA Vcc_plane_perimeter Vcc FPGA pkg Vcc FPGA int volts volts vol volts 1.5 L7. Lpkg_FPGA Lattach_FPGA Lvia Lspread 11 C3 C1 C2 **FPGA current** L4 L8 L3 L6 FPGA int plane bypass Lvia Lattach FPGA Lpkg FPGA Lspread 11 11 Gnd_plane_perimeter Gnd_FPGA_pkg 11 Gnd_FPGA_int Gnd_plane_FPGA volts volts volts volts

Steve Weir, Scott McMorrow, Teraspeed® Consulting Group LLC, "High Performance FPGA Bypass Filter Networks," DesignCon 2005, Santa Clara, CA, February 2005.





Effects of spreading Inductance in PDS

- Ising position 9 & 11 as I/O & core power position the effects of spreading inductance in the planes can be seen.
- Operation Demonstrates why measuring across a cap for capacitorin-system measurement isn't accurate.

Steve Weir, Scott McMorrow, Teraspeed® Consulting Group LLC, "High Performance FPGA Bypass Filter Networks," DesignCon 2005, Santa Clara, CA, February 2005.



This paper uses the concept of proper capacitor placement on a PC board to improve circuit performance.

Decoupling Strategies for Printed Circuit Boards Without Power Planes

Hwan W. Shim, Theodore M. Zeef, Todd Hubing EMC Labrotory University Missouri-Rolla Rolla, MO



* Presented at the August 2002 IEEE EMC Symposium, Minneapolis, MN - TU-PM-G-5, Volume 1, page258

Note: X2Y has expanded the testing with this PC board; further information can be found at this link: <u>#3001 - X2Y® Solution for Decoupling Printed Circuit Boards</u>

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X2Y Application Note #3001 - X2Y® Solution for Decoupling Printed Circuit Boards





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The X2Y[®] design maximizes mutual inductance to reduce parasitic inductance. Inside X2Y[®], *every other electrode layer* within the single component body is in opposition to cancel the magnetic flux.





Flux lines cancel outside of component body boundaries







Flux lines cancel *inside* of component body boundaries



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- Summary <u>Myth #5</u> Bypass capacitor placement with respect to ICs or other caps is not very critical.
- Distance between caps and IC should be minimized to reduce spreading incluctance.
- Spacing between cape day reduce or improve performance if external coupling occurs.
 - Depends on the direction of current.
 - Inter-digitate ourrent flow through std. MLCC Technology to improve performance.
 - Use technology that minimizes external coupling and inter-digitated current flow (X2Y[®] Technology).





<u>Myth #6</u> – Low-inductive caps are not useful on typical PCBs because via and mounting parasitics limit their effectiveness.





Reverse-Aspect-Ratio (LL) Caps – Capacitor-only

 LL caps show lower inductive performance on microstrip PCB.



Technology In Balance WHERE SIGNAL INTEGRITY MEETS EMC

PDS Placement & Mounting Parasitics



Reverse-Aspect-Ratio (LL) Caps – Capacitor-in-system

- Mounted with vias, LL caps (6 vias) have the same performance as MLCC caps (4 vias).
- LL caps are limited by mounting parasitics.



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Frequency (MHz)

Multi-Parallel Vias

 MLCC – going from 2 to 4 vias improves impedance by 150 mΩ
 @ 100 MHz.



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Via & Pad Geometries

- Optimized placement and routing of the vias & pads to minimize inductance.
- Considerations should include:
 - Via
 - Diameter
 - Length
 - Location
 - Trace/Pad
 - Width
 - Length



	Hole Diameter 0.020 inches								
Via	a length: (inches)	0603 skinny	0603 fat	0603 end	0603 side	0402 end	0402 side		
	.004	1.51	0.89	0.42	0.33	0.38	0.21		
	.006	1.66	1.12	0.53	0.38	0.44	0.25		
	.010	2.13	1.47	0.68	0.51	0.58	0.32		
	.020	2.68	2.07	1.07	0.67	0.82	0.43		

Hole Diameter 0.010 inches

	Via length: (inches)	0603 skinny	0603 fat	0603 end	0603 side	0402 end	0402 side
	.004	1.51	0.95	0.50	0.36	0.42	0.26
	.006	1.77	1.17	0.59	0.46	0.50	0.32
	.010	2.18	1.52	0.77	0.61	0.67	0.40
	.020	2.87	2.23	1.16	0.85	1.01	0.60

Howard Johnson, PhD, "Parasitic Inductance of a Bypass Capacitor II," HIGH-SPEED DIGITAL DESIGN – online newsletter Vol. 6 Issue 9, Signal Consulting, Inc.

Milliorn, Gary, "Power Supply Design for PowerPCTM Processors," Freescale Semiconductor Application Note AN2447, Rev. 1.1, Sept 2004.

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Inter-digitated vias

- Mutual inductance between vias cancel.
- Lowers over-all net inductance of vias, thus mounting inductance of caps.
- Inter-digitated caps are ideal to use minimize pad/trace distance to vias.



Steve Weir, Scott McMorrow, Teraspeed® Consulting Group LLC, "High Performance FPGA Bypass Filter Networks," DesignCon 2005, Santa Clara, CA, February 2005.



Minimize distance between PCB planes and capacitor (Via Length).

Extra via length between capacitor pad and PCB planes adds inductance.



Larry Smith, Raymond Anderson, Doug Forehand, Tom Pelc, and Tanmoy Roy, "Power Distribution System Design Methodology and Capacitor Selection for Modern CMOS Technology," IEEE Transaction on Advanced Packaging, August 1999, pages 284-291.



Summary <u>Myth #6</u> – Low-inductive caps are not useful on typical PCBs because via and mounting parasitios limit their effectiveness.

Solution Control State Stat

- Multiple parallel vias
- Inter-digitate vias lower over-all net via inductar e.
- Use Inter-digitated caps to minimize pad/trace distance from cap to via.
- Minimize distance between planes and caps.



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PDS with Low-Inductive Capacitors



<u>MLCC vs. X2Y®</u> on a Passive Xilinx FPGA PCB.
 (104) 0402 <u>MLCC</u> vs. (20) 0603 <u>X2Y®</u>
 (208) vias - <u>MLCC</u> vs. (120) vias - <u>X2Y®</u>
 Saves PCB real-estate!

Steve Weir, Scott McMorrow, Teraspeed® Consulting Group LLC, "High Performance FPGA Bypass Filter Networks," DesignCon 2005, Santa Clara, CA, February 2005.



Table 1, Mounted Inductance, Comparative Conventional and X2Y³

	Capacitors on Component Side							Capacitors on Back side ⁴		
H1	0.005	0.020	0.005	0.020	0.005	0.012	0.012	0.005	0.005	0.005
H2	0.014	0.003	0.003	0.001	0.001	0.038	0.038	0.014	0.003	0.001
s	0.03	0.03	0.03	0.03	0.03	0.032	0.044	0.03	0.03	0.03
D	0.01	0.01	0.01	0.01	0.01	0.02	0.02	0.01	0.01	0.01
K1 D/S	0.33	0.33	0.33	0.33	0.33	0.63	0.45	0.33	0.33	0.33
L / via pH	318	393	76	217	40	590	629	1580	1530	1540
L 0603	1052	1290	662	935	579	1500 ⁵	1760	3670	3560	3590
L 0402	952	1190	552	835	479	1400	1660	3570	3460	3490
L X2Y	267	355	117	223	90	435	531 [°]	1250	1210	1220
Caps req'd 0603	3.9	3.6	5.6	4.2	6.5	3.4	3.3	2.9	2.9	2.9
Caps req'd 0402	3.6	3.3	4.7	3.7	5.3	3.2	3.1	2.9	2.9	2.9
Caps req'd X2Y	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0	1.0

Steve Weir, Scott McMorrow, Teraspeed® Consulting Group LLC, "High Performance FPGA Bypass Filter Networks," DesignCon 2005, Santa Clara, CA, February 2005.



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<u>Myth #7</u> – Low-inductive and multi-terminal caps are cost prohibitive.



Component Cost vs. System Cost

Cost/Build-of-Materials (BOM)					
Number of cap	X2Y [®] is a 1:3 to 1:7 replacement over standard MLCC Technology. (Ratio depends on PCB thickness and plane height.)				
Number of vias	MLCC Technology typically used (2) vias per capacitor, where as X2Y [®] uses (6) vias. For a 1:3 ratio X2Y [®] uses the same number of via, for a 1:7 ratio X2Y [®] uses 6 vias and MLCC would use 14 which would be a 42.8% savings.				
Placement Cost	Placement cost depends on process, materials and volume used during manufacturing and is largest and hardest value to quantify.				
PCB real-estate	X2Y [®] saves space.				
Number of layers for routing	Fewer vias for capacitor allows for more room for routing.				
Assembly time	Fewer capacitors reduces assembly time.				
Number solder joints	Fewer solder joints reduces assembly time.				
Number via drills	Fewer via drills reduces assembly time and cost.				
Number pick-and-place machines	Fewer capacitors reduces the number of pick-and-place machines needed in production (capital cost).				
Reliability	Reliability affects warranty cost, manufacturing cost, and customer satisfaction.				
Number of attachments	Reducing the number of attachments on PCB improves reliability.				
solder joints	Reducing the number of solder joints on PCB improves reliability.				
Number of vias	Reducing the number of vias on PCB improves reliability.				
Number of components	Reducing the number of components on PCB improves reliability.				



Summary <u>Myth #7</u> – Low-inductive and multi-terminal caps are cost prohibitive.

- Our cost more.
 Our cost more.
- System cost lov-inductive caps (IPDs) offer substantial cost savings.
- Roadmap for NEMI published in 2003 predicted cost savings for IPDs starting in 2005.

Joseph Dougherty, John Galvagni, Larry Marcanti, Rob Sheffield, Peter Sandborn, and Richard Ulrich, "The NEMI Roadmap: Integrated Passives Technology and Economics," CARTS 2003, Scottsdale, AZ, April 2003.





Multi-plane Decoupling

- Observe the second s
- A single X2Y[®] can be used for 2 different power planes.



<u>Myth #8</u> – Multiple power planes require more decoupling capacitors.















Note: Scale differences.

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Summary <u>Myth #8</u> – Multiple power plane require more decoupling capacitors.

All power planes require decorpling caps.

Conventional capacitor technology can only decouple one plane.

Output State of the second simultaneously decouple 2 power planes, significantly reducing the number of caps typically required.



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<u>Myth #9</u> – X2Y[®] is just a capacitor.



X2Y[®] Technology – Circuit 1 & Circuit 2

- Ocapacitive Circuit
 - Circuit 1 3 conductor
 - Circuit 2 2 conductor
- 4 terminal device
- Layout attachment is interdigitated
- Note: X2Y[®] in this presentation has been Circuit 2 unless noted (multi-plane decoupling)





X2Y[®] structural features for low-inductance.

- Shorter current path to ground, therefore smaller current loops.
- Dual current path to ground.
- Opposing current flow internal to the device = cancellation of mutual inductance.
- The X2Y footprint results in lower mounted inductance.















X2Y[®] Structural Benefit – shorter path to ground, which creates a smaller current loop when attached to the PCB.





X2Y[®] Structural Benefit – dual ground connection to the PCB.



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X2Y[®] Structural Benefit – opposing current flow to a <u>single</u> ground connection and resulting benefit of flux cancellation.



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X2Y[®] Structural Benefit – opposing current flow to a <u>dual</u> ground connection and resulting benefit of flux cancellation.



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X2Y[®] vs. other IPD (Integrated Passive Devices) (a) The X2Y[®] Technology Advantage

	X2Y [®] Technology	Other IPD		
Package Size	Can be manufactered in any package size and still maintain low-inductive performance.	Limited to 0612 or smaller package size to maintain low- inductive perfomance.		
Capacitance Value	Can be manufactered in any capacitve value current technology allows and still maintain low-inductive performance due to package size advantage.	Limited to smaller package sizes for low-inductive performance, thus limited to the amount of capacitance smaller package sizes will allow.		
Number of Terminations	4	8		
Number of Solder Joints	4	8		
Number of Vias	6	8		
Via Size	Any	Small or micro-vias, large vias increase pad inductance.		
Low-Inductance	Premier	Good		
Sourcing	Multiple Manufactures	Single Sourced		
Cost	Good value	Expensive		



Summary <u>Myth #9</u> – X2Y[®] is just a capacitor.

- Second Structure Structure of Comparison (Comparison of Comparison) (Comparison (Comparison (Comparison)) (Comparison) (Comparison)
- X2Y[®] requires connections at all 4 terminals to fully realize the performance benefits.
 X2Y[®] is the promion IPD Technology.
- Solution For more application information on the X2Y[®] Technology go to <u>www.x2y.com</u>.





Questions? Please Contact: X2Y Attenuators, LLC 37554 Hills Tech Dr. Farmington Hills, MI 48331 248-489-0007 x2y@x2y.com

Additional Resources

- Sanders, Muccioli, North, and Slattery, "<u>The Quantitative Measurement of the Effectiveness of Decoupling Capacitors in Controlling Switching Transients</u> from Microprocessors," CARTS 2005 USA, Palm Springs, CA, March 2005.
- Steve Weir, Scott McMorrow, Teraspeed® Consulting Group LLC, "<u>High Performance FPGA Bypass Filter Networks</u>," DesignCon 2005, Santa Clara, CA, February 2005.
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- Steve Wier, " Considerations for Capacitor Selection in FPGA Designs," CARTS 2005 USA, Palm Springs, CA, March 2005.
- Joseph Dougherty, John Galvagni, Larry Marcanti, Rob Sheffield, Peter Sandborn, and Richard Ulrich, "The NEMI Roadmap: Integrated Passives Technology and Economics," CARTS 2003, Scottsdale, AZ, April 2003.
- Steve Weir, Teraspeed® Consulting Group LLC, "<u>Does position matter? Locating bypass capacitors for effective power distribution and EMC control</u>", Santa Clara Valley Chapter of the IEEE-EMC Society, January 2005.
- Milliorn, Gary, "Power Supply Design for PowerPCTM Processors," Freescale Semiconductor Application Note AN2447, Rev. 1.1, Sept 2004.
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7/19/2005